Unit: mm

TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ($L^2 - \pi - MOS V$)

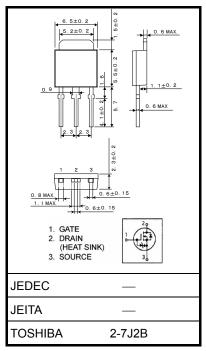
2SK4019

Chopper Regulator, DC/DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON-resistance : $R_{DS (ON)} = 0.17 \Omega (typ.)$
- High forward transfer admittance : |Y_{fs}| = 4.5 S (typ.)
- Low leakage current : I_{DSS} = 100 μA (max) (V_{DS} = 100 V)
- Enhancement mode : $V_{th} = 0.8 \sim 2.0 \text{ V} (V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Character	istic	Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	100	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V _{DGR}	100	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	۱ _D	5	A	
	Pulse (Note 1)	I _{DP}	20	А	
Drain power dissipatio	n (Tc = 25°C)	PD	20	W	
Single-pulse avalanch	e energy (Note 2)	E _{AS}	180	mJ	
Avalanche current		I _{AR}	5	А	
Repetitive avalanche e	energy (Note 3)	E _{AR}	2	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	



Weight: 0.36 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristic	Symbol	Мах	Unit
Thermal resistance, channel to case	R _{th (ch−c)}	6.25	°C / W
Thermal resistance, channel to ambient	R _{th (ch−a)}	125	°C / W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 11.6 mH, R_G = 25 Ω , I_{AR} = 5 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

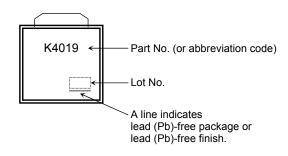
Electrical Characteristics (Ta = 25°C)

Chara	cteristic	Symbol	Test Condition	Min	Тур.	Мах	Unit
Gate leakage cu	urrent	I_{GSS} $V_{GS} = \pm 16 V, V_{DS} = 0 V$		_	_	±10	μA
Drain cutoff curr	ent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V		_	100	μA
Drain-source br voltage	eakdown	V _(BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON-resistance		5	V _{GS} = 4 V, I _D = 2.5 A		0.22	0.30	
		R _{DS (ON)}	V _{GS} = 10 V, I _D = 2.5 A	_	0.17	0.23	Ω
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 2.5 A	2.0	4.5		S
Input capacitance	ce	C _{iss}		_	500	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	80	_	pF
Output capacitance		C _{oss}		_	190		
Switching time	Rise time	tr	$v_{GS} \stackrel{10V}{_{0V}} \qquad I_{D} = 2.5A$ $v_{GS} \stackrel{10V}{_{0V}} \qquad R_{L}$ $= 20\Omega$	_	17	_	
	Turn-on time	t _{on}		_	25	_	20
	Fall time	t _f		_	50	_	ns
	Turn-off time	t _{off}	$V_{DD} = 50V$ Duty $\leq 1\%$, t _w = 10 μ s		195	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	22	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 80 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$		15	—	nC
Gate-drain ("Miller") charge		Q _{gd}		—	7	—	

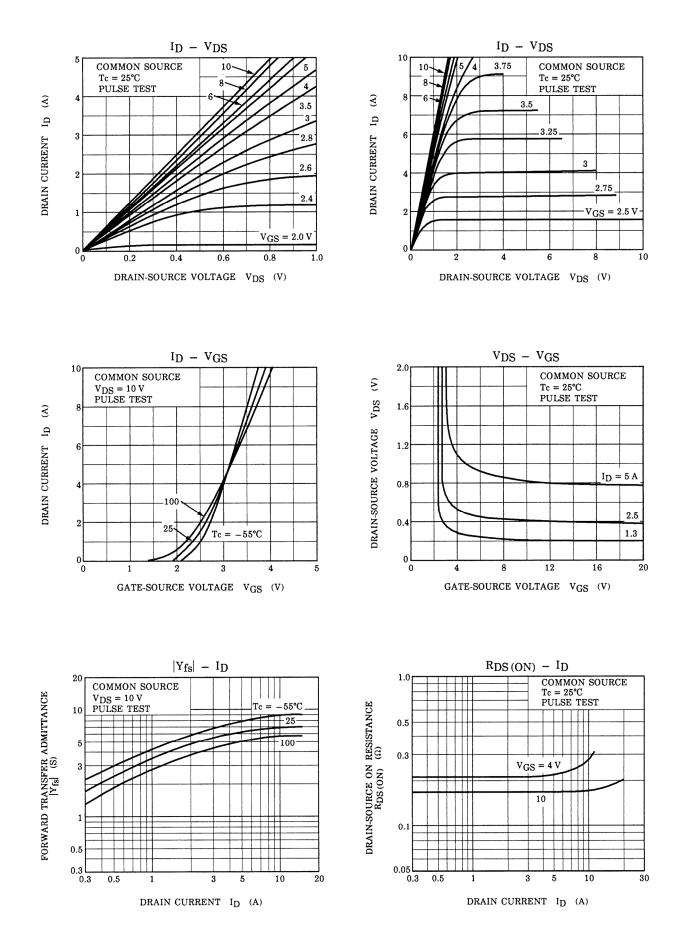
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	-	_	_	5	A
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	20	A
Forward voltage (diode)	V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I_{DR} = 5 A, V_{GS} = 0 V, dI_{DR} / dt = 50 A / μ s		160		ns
Reverse recovery charge	Q _{rr}			0.28	_	μC

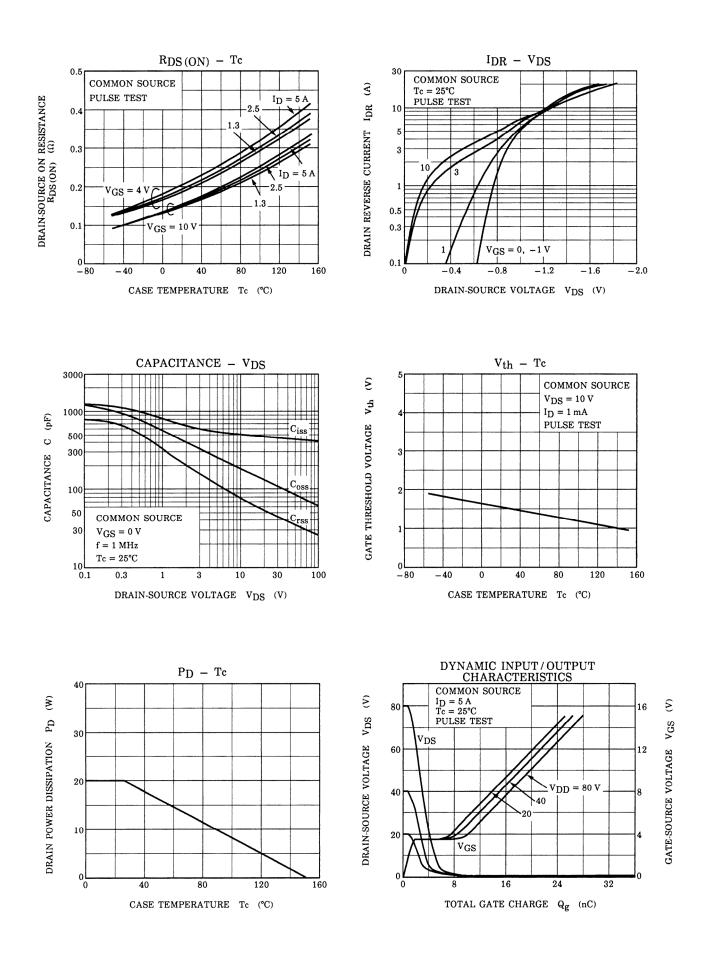
Marking



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DRAIN CURRENT

10

5

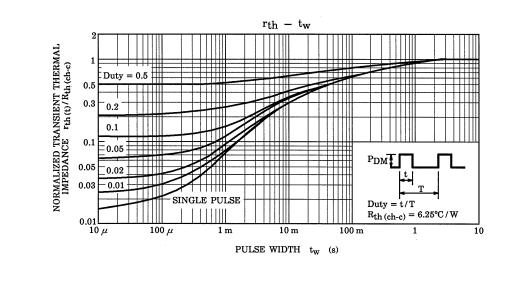
3

1

0.5

0.3

0.1L 0.3



100 50 30 I_D MAX. (PULSE) % 100 μs%

ID MAX. (PULSE) X

temperature.

1

ID MAX. (CONTINUOUS)

DC OPERATION $Tc = 25^{\circ}C$

% SINGLE NONREPETITIVE

3

10

DRAIN-SOURCE VOLTAGE V_{DS} (V)

 $PULSE \quad Tc = 25^{\circ}C$

Curves must be derated linearly with increase in

SAFE OPERATING AREA

ms×

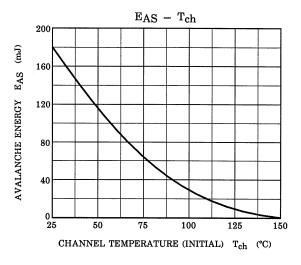
VDSS MAX

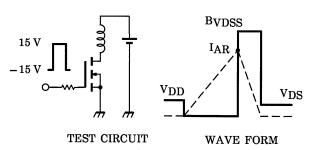
100

300

30

|0 msЖ





 $\begin{array}{ll} \mathrm{R}_{G} = 25 \ \Omega \\ \mathrm{V}_{DD} = 25 \ \mathrm{V}, \ \mathrm{L} = 11.6 \ \mathrm{mH} \end{array} \end{array} \qquad \mathrm{E}_{\mathrm{AS}} = \frac{1}{2} \cdot \mathrm{L} \cdot \mathrm{I}^{2} \cdot \left(\frac{\mathrm{B}_{\mathrm{VDSS}}}{\mathrm{B}_{\mathrm{VDSS}} - \mathrm{V}_{\mathrm{DD}}} \right. \\ \end{array}$

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20070701-EN

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